

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination REILLY ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Muhlberger et al. "Single Photon Ionization (SPI) via Incoherent VUV-Excimer Light: Robust and Compact Time-of-Flight Mass Spectrometer for On-line, Real-Time Process Gas Analysis". Anal. Chem. 2002, 74:3790-3801.
	W	Baldwin et al. "Matrix-Assisted Laser Desorption/Ionization coupled with Quadrupole/Orthogonal Acceleration Time-of-Flight Mass Spectrometry for Protein Discovery, Identification, and structural analysis", Anal. Chem. 2001, 73:1707-1720.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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